Cameca Instruments
Local Electrode Atom Probe (LEAP® 4000X HR)

Techniques/Capabilities:
• Atom Probe Tomography
• Laser and voltage pulsing
• 200 kHz high voltage pulse generator, 1 MHz laser
• Reflectron energy-compensating lens
• Crossed delay line, single atom position-sensitive detector
• Comprehensive suite for data analysis including IVAS, PoSAP and ORNL-developed software

Current Research Activities:
Atomic level 3D microstructural characterization of solute distributions in a wide range of materials

Contact: Jon Poplawsky, poplawskyjd@ornl.gov, (865) 576-4965

Ti(C,O,N) precipitate at a triple point and nanoclusters on grain boundaries in a nanostructured ferritic steel.